Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/626,548	MAEKAWA, YOHEI	
Examiner	Art Unit	
Michael Y. Won	2155	

	SEAR	CHED	
Class	Subclass	Date	Examiner
709	209, 220	11/5/2007	MVV
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INT	ERFEREN	CE SEARCH	ED
Class	Subclass	Date	Examiner
709	220	11/5/2007	MW
			

SEARCH N (INCLUDING SEARC)
	DATE	EXMR
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	. 11/5/2007	MW
NPL SEARCH: IEEE	11/5/2007	MW
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